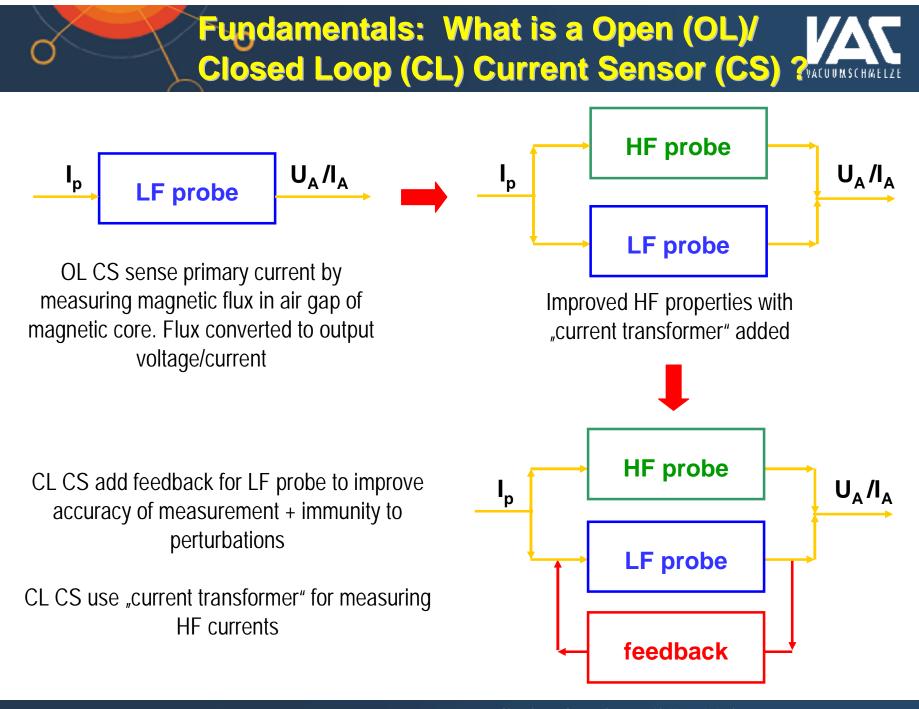
Closed Loop Current Sensors with Magnetic Probe

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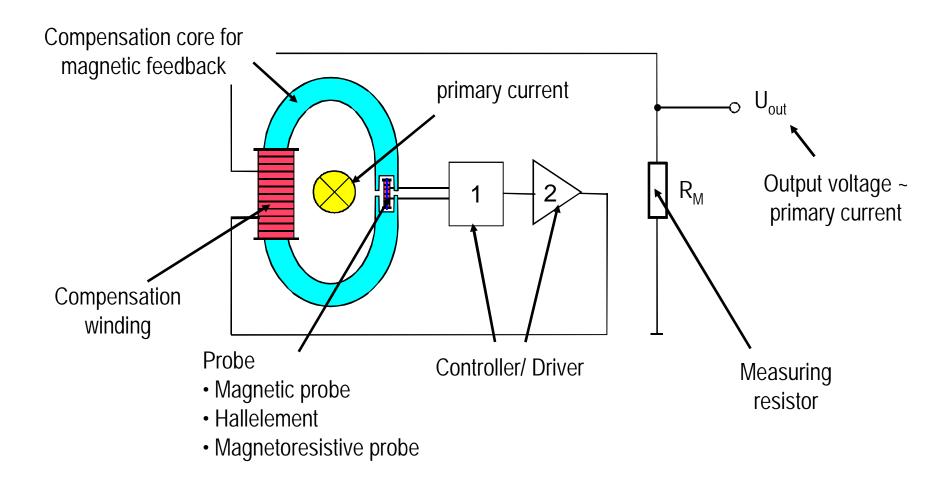
ECPE Seminar Sensors in Power Electronics 14./15.03.2007, Erlangen, Germany Dr. Dirk Heumann, Hr. Klaus Reichert

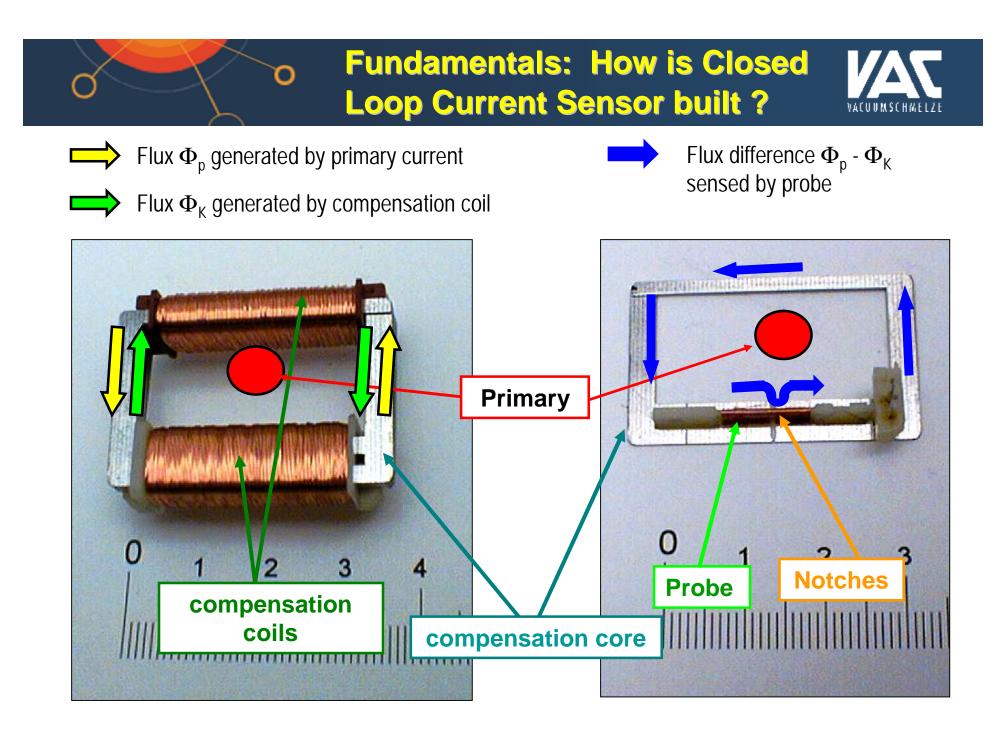




o Fundamentals: What is the setup of a Closed Loop Current Sensor ? VACUUMSCHMELZE

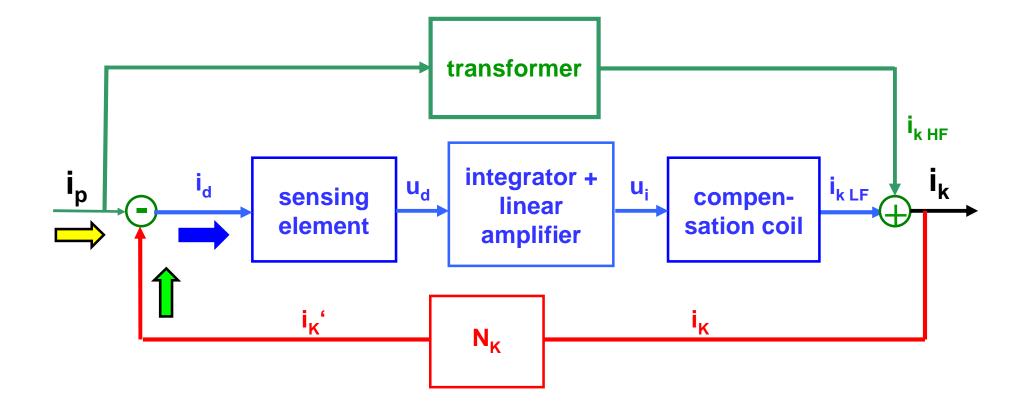
Closed loop CS regulate difference between magnetic fluxes, generated by primary current and compensation current, to zero \Rightarrow compensation current ~ primary current. Control loop improves accuracy, reduces internal (electronics) + external perturbations (temperature,...).





Fundamentals: What is the Closed Loop (Control Loop) ?

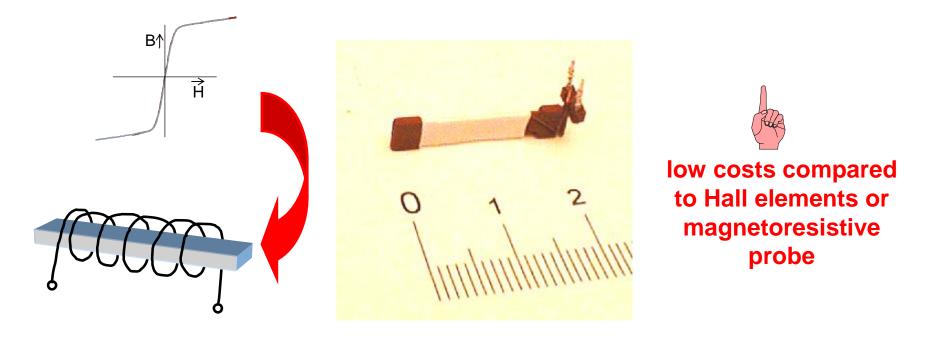
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Fundamentals: What is a Magnetic Probe ?



Probe = one strip of amorphous alloy VITROVAC (thickness ~20 μ m, 10mm*3mm) with 150 turns Z-shaped hysteresis loop \Leftrightarrow high L, if not close to saturation, low L, if saturated ~ magnetic switch



Magnetic Probe does not require uniform field distribution of compensation core in contrast to Hall element probe:

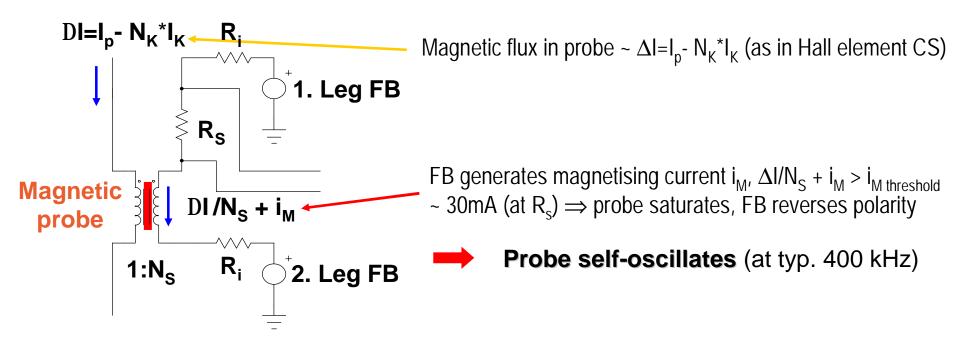
 \Rightarrow smaller, **low-cost compensation core** can be used



14.03.07

Closed Loop Current Sensors with Magnetic Probe

Fundamentals: How does a Magnetic Probe work?



Voltages at probe ~ ΔI , R=2*R_i+R_s \Rightarrow saturation in one direction faster than in other

Oscillation pulse-width-modulated

 $\Delta I=0A \Rightarrow D=50\%$, D increases by ~20% for $\Delta I=1A \Rightarrow D=30\%$ for $\Delta I=+1A$, D=70% for $\Delta I=-1A$ Conversion into voltage by averaging $U_a \sim (D-50\%)^*U_S$



Output voltage probe ~ DI

Fundamentals: What are the properties of a Magnetic Probe ? 1000 50 Output voltage Magnetic Probe [mV] Hall element [mV] Gain Hall element 800 40 ~ 1 mV/A **Gain Magnetic** 600 30 Probe ~ 500mV/A 400 20 200 10 **Offset Hall element** 0 0 100-200mA **Dutput voltage** -200 -10 **Operating** -400 -20 range CL CS -600 -30 **Offset Magnetic** -800 -40 Probe < 5mA -1000 -50 -15 10 20 -20 -10 5 15 **Primary current [A]**

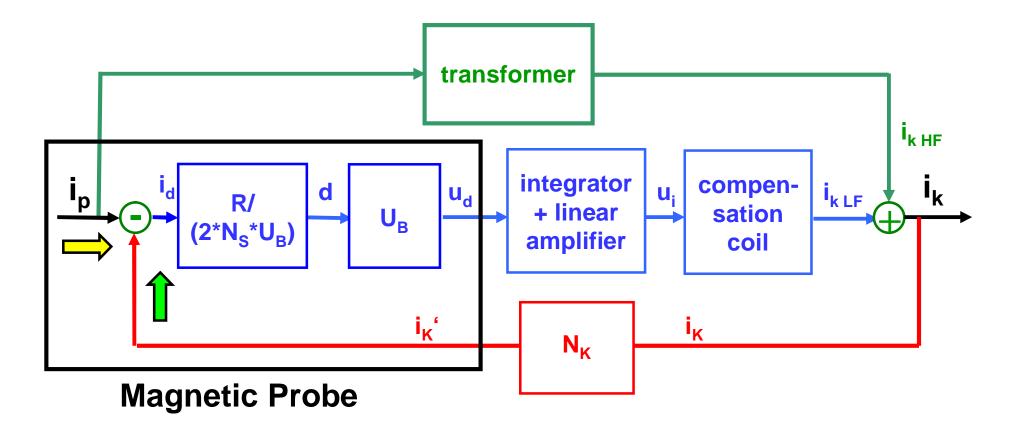
Further properties of Magnetic Probe:

• basically no temperature drift (duty-cycle not dependent on absolute saturation induction values, only on symmetry $B_{pos. sat} = -B_{neg. sat}$) \Rightarrow superior to Hall elements

• probe noise with lower magnitude, higher frequency (400kHz) than semiconductor noise of Hall element \Rightarrow easier to filter out

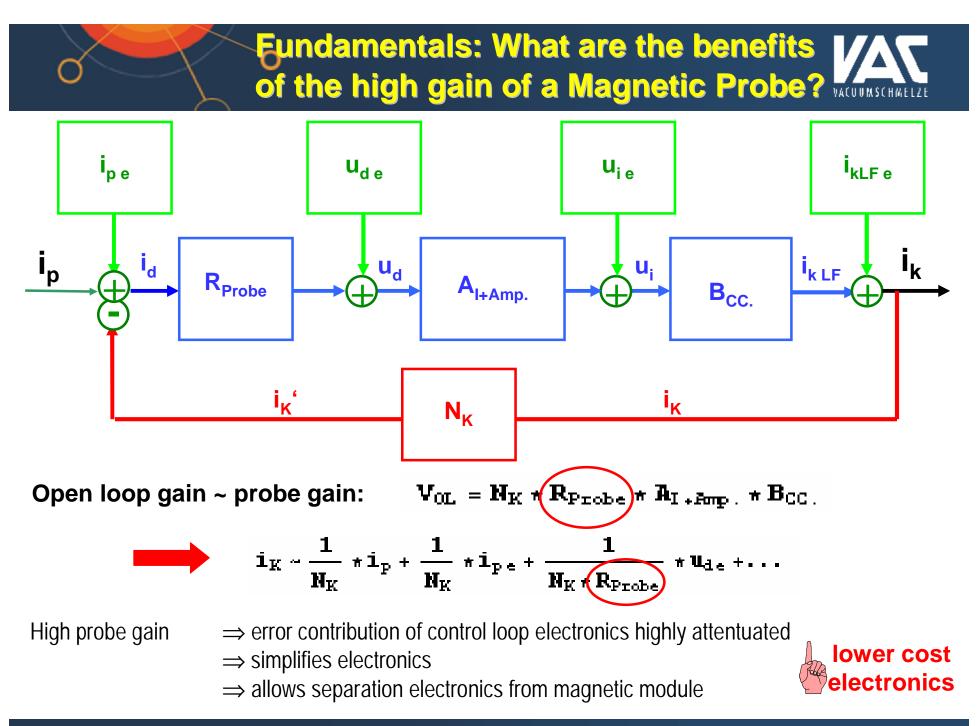
Fundamentals: Control loop with Magnetic Probe revisited

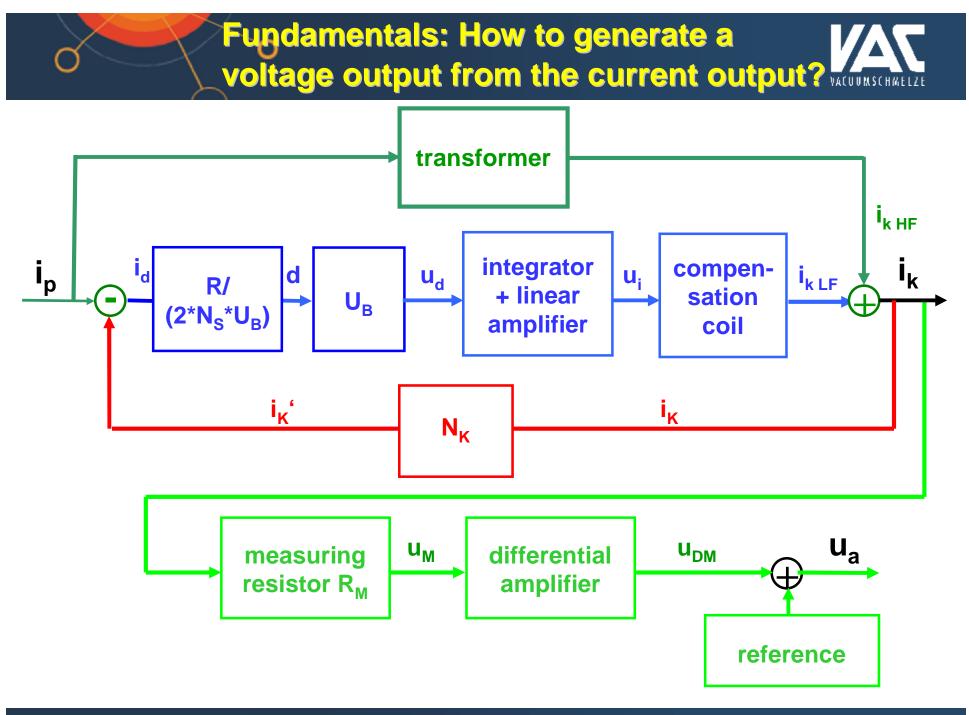




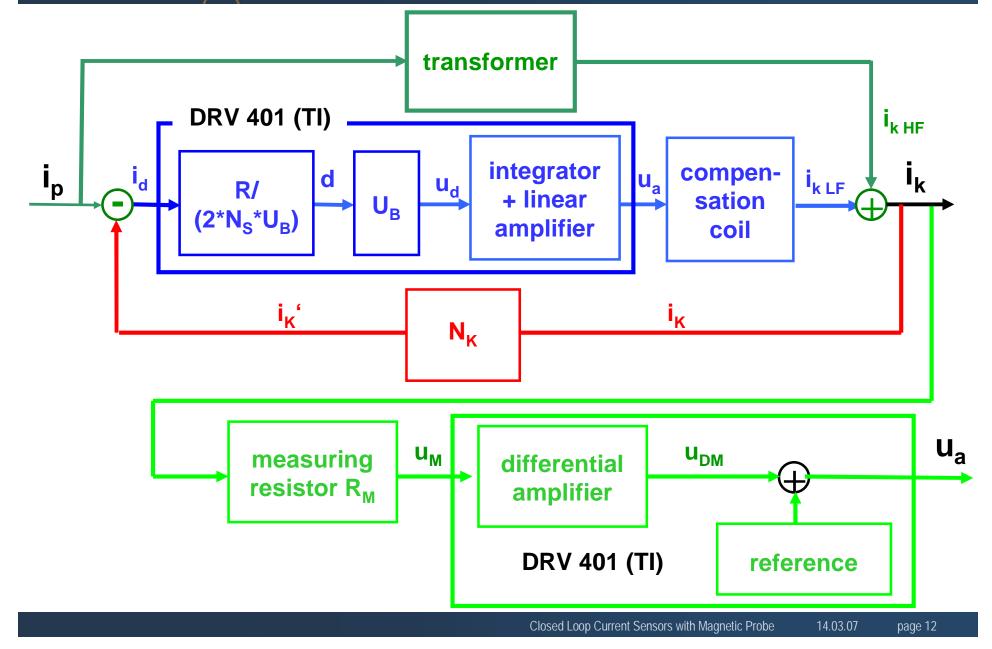
Verification of gain of Magnetic Probe:

Typical values: R ~ 150 Ω , N_S~150 \Rightarrow u_d/i_d ~ 150 Ω /(2*150) = 500mV/A



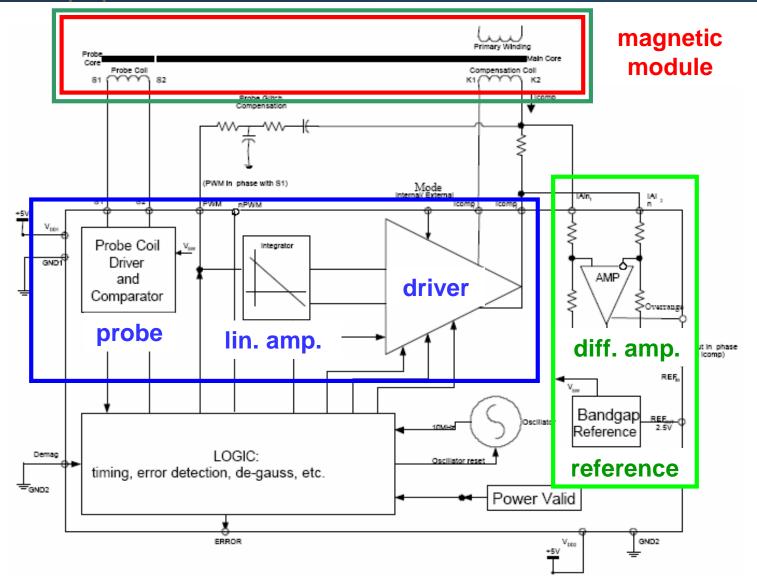


- DRV401: Integration of Control Loop + voltage output into TI-IC DRV401



DRV401: Functional blocks Basic functionality



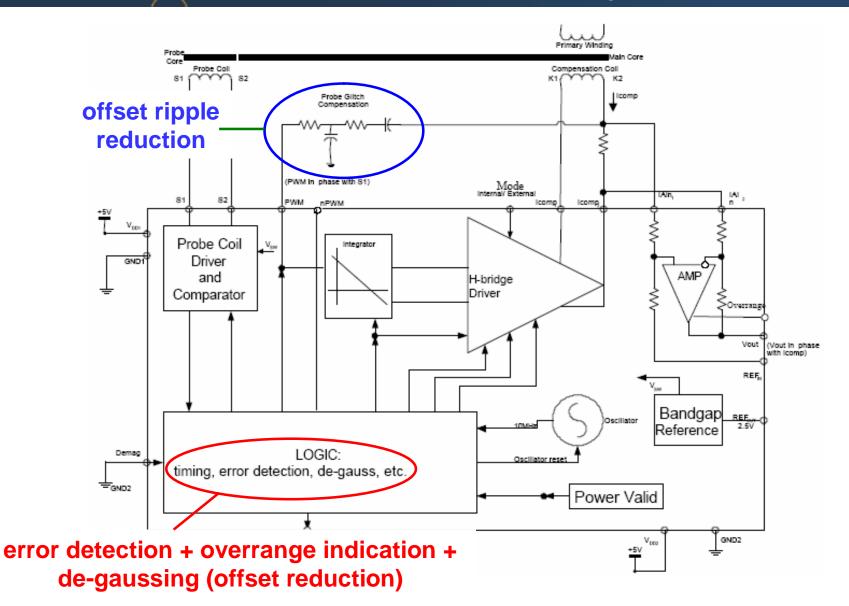


http://focus.ti.com/docs/prod/folders/print/drv401.html

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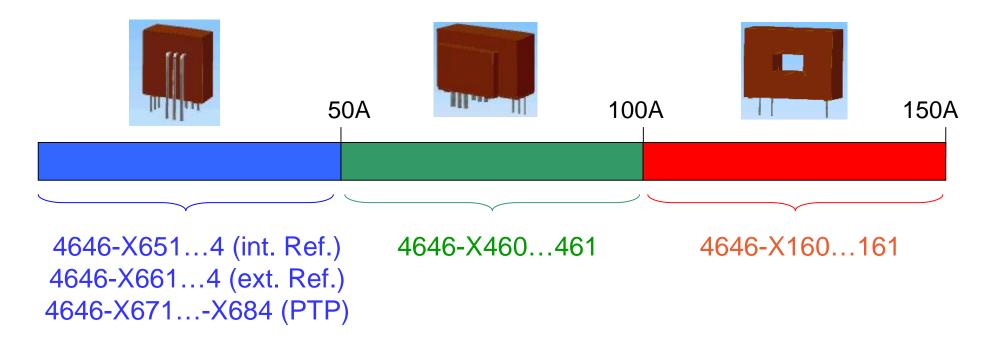
DRV401: Functional blocks Added functionality





Magnetic modules: Magnetic Probe CS with 5V single supply + voltage output

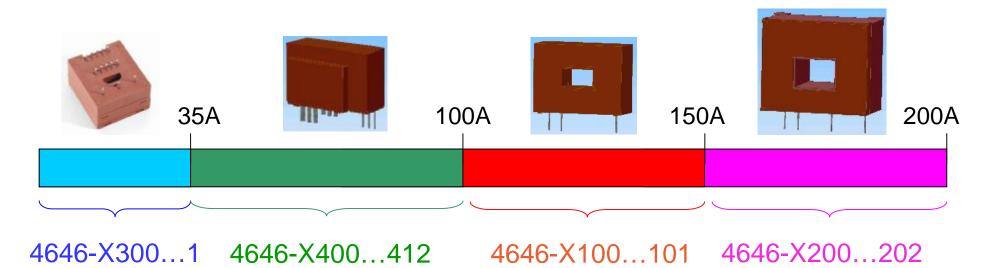
5V single supply voltage current sensors up to I_{PN} = 150A:



Also available as passive CS with external DRV401.

Magnetic modules: Magnetic Probe CS with ±15V dual supply + current output

 \pm 15V dual supply voltage current sensors (until now) up to I_{PN} = 200A:



<u>+</u>15V dual supply voltage current sensors have external half-bridge, driven by H-bridge driver of DRV401. Current range will be extended up to $I_{PN} = 700A$ with external PWM-half-bridge.

Also available as passive CS with external DRV401.

Comparison between CL Magnetic Probe, CL Hall element CS

Typical 100A CS	CL magnetic probe	CL Hallelement	OL Hall element
Offset current I_0 (ref. to prim. current)/ Hysteresis offset current I_{0H} ($I_P > 3^*I_{PN}$)	< 100 mA	< 150 mA	< 5001000 mA
Temperature drift offset current I _{0T} (2585°C)	< 50mA	< 250500 mA	< 500800 mA
Gain error F _i	< 0.10.5 %		< 1 %
Temperature drift gain F _{iT} (2585°C)	< 0.10.2%		< 2%
Linearity F _{Li}	< 0.10.2 %		< 0.7 %
3dB-corner frequency	200 kHz		50kHz
Response time (short circuit)	< 0.51µsec		< 3 µsec

Offset current/hysteresis offset current at CL Magnetic Probe CS related to compensation core, can be reduced by factor of 10 possible by de-gaussing (in-built feature of DRV401).



Advantages of CL CS derive from compensating influences from amplifier electronics, compensation core (modulation),... :

- lower offset, gain error and linearity errors
- lower temperature + long-term drift of gain and linearity errors
- wider frequency range + shorter response time

Advantage of OL CS :

 \cdot no compensation current \mathbf{P} lower power consumption

Summary:

- CL CS with Magnetic/Hall element Probe technically superior to OL CS
- CL CS with Magnetic Probe at same cost level as advanced OL CS

OCOMPARISON OF CL current sensors: Magnetic Probe to Hall element CS

Compensation core + compensation winding-related properties similar:

- gain error + linearity error
- hysteresis offset current
- 3-dB corner frequency + response time

Advantages of CS with Magnetic Probe derive from probe:

- basically zero offset
- lower temperature drift of offset
- lower long-term drift of offset
- no low frequency output noise as from Hall element probe

Summary:

- CL Magnetic Probe CS technically superior to CL Hall element CS
- CL CS with Magnetic Probe at lower cost than CS with Hall element